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Potentiometers for use in electronic equipment – Part 1: Generic specification

INTERNATIONAL ELECTROTECHNICAL COMMISSION

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

POTENTIOMETERS FOR USE IN ELECTRONIC EQUIPMENT –

Part 1: Generic specification

FOREWORD

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International Standard IEC 60393-1 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment.

This third edition cancels and replaces the second edition published in 1989 and constitutes a technical revision, including minor revisions related to tables, figures and references.

This edition contains the following significant technical changes with respect to the previous edition:

- implementation of Annex H which replaces Section 3 of the previous edition.

The text of this standard is based on the following documents:

FDIS	Report on voting
40/1897/FDIS	40/1914/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all the parts of the IEC 60393 series, under the general title *Potentiometers for use in electronic equipment*, can be found on the IEC web site.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

POTENTIOMETERS FOR USE IN ELECTRONIC EQUIPMENT –

Part 1: Generic specification

1 General

1.1 Scope

This part of IEC 60393 is applicable to all types of resistive potentiometers, including lead-screw actuated types, presets, multi-turn units, etc. to be used in electronic equipment.

It establishes standard terms, inspection procedures and methods of test for use in sectional and detail specifications of electronic components for quality assessment or any other purpose.

It has been mainly written, and the test methods described, to conform to the widely used single-turn rotary potentiometer with an operating shaft.

For other types of potentiometers:

- the angle of rotation may be several turns;
- the reference to an operating shaft shall apply to any other actuating device;
- the angular rotation shall be taken to mean mechanical travel of the actuating device;
- a value for force shall be prescribed instead of a value for torque if the actuating device moves in a linear instead of a rotary manner.

These alternative prescriptions will be found in the sectional or detail specification.

When a component is constructed as a variable resistor, i.e. as a two-terminal device, the detail specification shall prescribe the modifications required in the standard tests.

1.2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027-1, *Letter symbols to be used in electrical technology – Part 1: General*

IEC 60050 (all parts), *International Electrotechnical Vocabulary (IEV)*

IEC 60062, *Marking codes for resistors and capacitors*

IEC 60063:1963, *Preferred number series for resistors and capacitors*
Amendment 1 (1967)
Amendment 2 (1977)

IEC 60068-1:1988, *Environmental testing – Part 1: General and guidance*
Amendment 1 (1992)

IEC 60068-2-1:1990, *Environmental testing – Part 2: Tests – Tests A: Cold*
Amendment 1 (1993)
Amendment 2 (1994)

IEC 60068-2-2:1974, *Environmental testing – Part 2: Tests – Tests B: Dry heat*
Amendment 1 (1993)
Amendment 2 (1994)

IEC 60068-2-6, *Environmental testing – Part 2: Tests – Test Fc : Vibration (sinusoidal)*

IEC 60068-2-13, *Environmental testing – Part 2: Tests – Test M: Low air pressure*

IEC 60068-2-14:1994, *Environmental testing – Part 2: Tests – Test N: Change of temperature*
Amendment 1 (1986)

IEC 60068-2-17, *Environmental testing – Part 2: Tests – Test Q: Sealing*

IEC 60068-2-20:1979, *Environmental testing – Part 2: Tests – Test T: Soldering*
Amendment 2 (1987)

IEC 60068-2-21, *Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices*

IEC 60068-2-27, *Environmental testing – Part 2: Tests – Test Ea and guidance: Shock*

IEC 60068-2-29, *Environmental testing – Part 2: Tests – Test Eb and guidance: Bump*

IEC 60068-2-30, *Environmental testing – Part 2-30: Tests – Test dB : Damp heat, cyclic (12 h + 12 hour cycle)*

IEC 60068-2-45:1980, *Environmental testing – Part 2: Tests – Test XA and guidance: Immersion in cleaning solvents*
Amendment 1 (1993)

IEC 60068-2-58, *Environmental testing – Part 2-58: Tests – Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)*

IEC 60068-2-78, *Environmental testing – Part 2-78 – Test Cab: Damp heat, steady state*

IEC 60410, *Sampling plans and procedures for inspection by attributes*

IEC 60617, *Graphical symbols for diagrams*

IEC 60915, *Capacitors and resistors for use in electronic equipment – Preferred dimensions of shaft ends, bushes and for the mounting of single-hole, bush-mounted, shaft-operated electronic components*

IEC 61249-2-7, *Materials for printed boards and other interconnecting structures – Part 2-7: Reinforced base materials clad and unclad – Epoxide woven E-glass laminated sheet of defined flammability (vertical burning test), copper-clad*

IECQ 001002-3, *IEC Quality Assessment System for Electronic Components (IECQ) – Rules of procedure – Part 3: Approval procedures*

IECQ 001005, see www.iecq.org\certificates for relevant information

ISO 1000, *SI units and recommendations for the use of their multiples and of certain other units*

ISO 9000, *Quality management systems – Fundamentals and vocabulary*